coatings

Correction

Correction: He et al. Mechanism and Structural Defects of Zinc Film Deposited on a Copper Substrate: A Study via Molecular Dynamics Simulations. *Coatings* 2025, *15*, 174

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In the original publication [1], there were a couple of errors involving figures and their captions.

A caption mistake occurred in the title of Figure 9a. Instead of FCCl, it should be FCC. The correct text of the figure caption appears below.

Figure 9. Dislocation distribution in zinc film: (**a**) FCC; (**b**) HCP (green line—1/6<112> Shockley partial dislocation; pink line—1/6<110> stair-rod ladder rod dislocation; blue line—1/3<100> Hirth dislocation; orange line—1/3<1-100> Shockley partial dislocation; red line—other dislocations).

There was a mistake in Figure 10b. The figure in the original manuscript is about the deposition rate data, the correct figure should be about the temperature data. The corrected Figure 10 appears below.

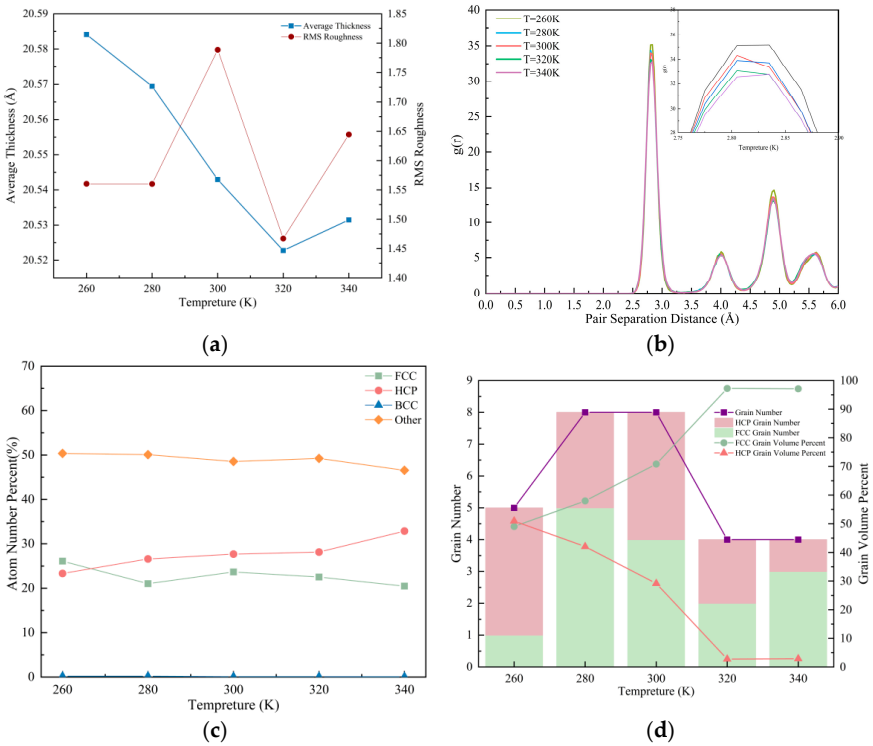


Figure 10. The polycrystal structure of zinc films varies with the deposition temperature: (**a**) film thickness and surface roughness; (**b**) radial distribution function; (**c**) number of atoms with specific structure type; (**d**) number of grains and structure type of polycrystalline films.

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There was a mistake in Figure 14a. The wrong name and unit of the *X*-axis data in the manuscript is ZDR (ps/atom); the correct name and unit is Deposition Rate (atom/ps). The figure in the original manuscript is about ZDR (ps/atom) data, the correct figure should be about Deposition Rate (atom/ps) data. The corrected Figure 14 appears below.

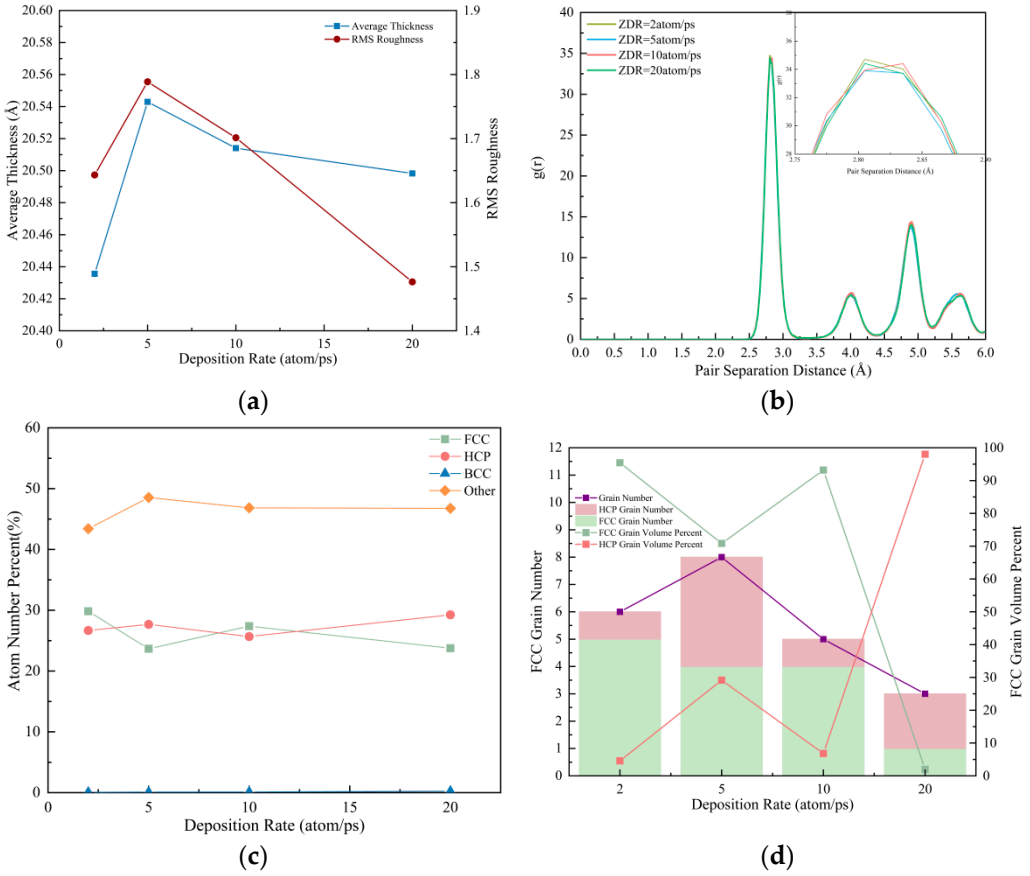


Figure 14. The change in the polycrystalline structure of zinc films with deposition rate: (**a**) film thickness and surface roughness; (**b**) radial distribution function; (**c**) number of atoms with specific structure type; (**d**) number of grains and structure type of polycrystalline films.

The authors state that the scientific conclusions are unaffected. This correction was approved by the Academic Editor. The original publication has also been updated.

Reference

1. He, X.; Qin, X.; Zhan, L. Mechanism and Structural Defects of Zinc Film Deposited on a Copper Substrate: A Study via Molecular Dynamics Simulations. *Coatings* **2025**, *15*, 174. [CrossRef]

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